MOSFET – Power, Single, **N-Channel** 30 V, 98 A

NVTYS003N03CL

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Paran	Symbol	Value	Unit		
Drain-to-Source Voltage			V _{DSS}	30	V
Gate-to-Source Voltage			V _{GS}	±20	V
Continuous Drain		$T_A = 25^{\circ}C$	۱ _D	23	А
Current R _{θJA} (Note 1)		$T_A = 100^{\circ}C$		16	
Power Dissipation $R_{\theta JA}$		$T_A = 25^{\circ}C$	PD	3	W
(Note 1)	Steady	$T_A = 100^{\circ}C$		2	
Continuous Drain	State	$T_{C} = 25^{\circ}C$	۱ _D	98	А
Current $R_{\theta JC}$ (Note 1)		$T_{C} = 100^{\circ}C$		70	
Power Dissipation		$T_{C} = 25^{\circ}C$	PD	59	W
R _{θJC} (Note 1)		$T_{C} = 100^{\circ}C$		30	
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \ \mu s$		I _{DM}	446	А
Operating Junction and Storage Temperature Range			T _J , T _{stg}	–55 to +175	°C
Source Current (Body Diode)			I _S	50	А
Single Pulse Drain-to-Source Avalanche Energy $(I_L = 7.4 A_{pk})$			E _{AS}	173	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			ΤL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

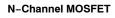
1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.

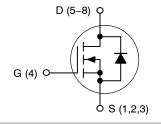


ON Semiconductor®

www.onsemi.com

V _{(BR)DSS}	R _{DS(on)} MAX	I _D MAX
30 V	$3.6~\mathrm{m}\Omega$ @ 10 V	98 A
30 V	5.1 mΩ @ 4.5 V	30 A







003N03CL = Specific Device Code А = Assembly Location

WL = Wafer Lot Y

= Year w

= Work Week

ORDERING INFORMATION

Device	Package	Shipping [†]
NVTYS003N03CLTWG	LFPAK33 (Pb-Free)	3000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{\theta JC}$	2.5	°C/W
Junction-to-Ambient - Steady State	$R_{\theta JA}$	47.2	0/00

2. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.

3. Surface-mounted on FR4 board using a 650 mm², 2 oz. Cu pad.

4. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

ELECTRICAL CHARACTERISTICS (T_J = $25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit	
OFF CHARACTERISTICS								
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V_{GS} = 0 V, I_D = 250 μ A		30			V	
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} / T _J				19		mV/°C	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 V,$	$T_J = 25^{\circ}C$			1.0	<u> </u>	
		$V_{DS} = 24 V$	T _J = 125°C			10	μΑ	
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 V, V_{GS}$	_S = ±20 V			±100	nA	
ON CHARACTERISTICS (Note 5)								
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_{D}$	= 250 μA	1.3		2.2	V	
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				-5.46		mV/°C	
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 30 A		2.7	3.6		
		V _{GS} = 4.5 V	I _D = 30 A		4	5.1	1 mΩ	
Forward Transconductance	9fs	V _{DS} = 1.5 V,	_D = 15 A		64		S	
Gate Resistance	R _G	$T_A = 25^{\circ}C$			0.8		Ω	
CHARGES AND CAPACITANCES								
Input Capacitance	C _{ISS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 15 V			1870			
Output Capacitance	C _{OSS}				983		pF	
Reverse Transfer Capacitance	C _{RSS}				30		1	
Capacitance Ratio	C _{RSS} /C _{ISS}	V_{GS} = 0 V, V_{DS} = 15 V, f = 1 MHz			0.016			
Total Gate Charge	Q _{G(TOT)}				12			
Threshold Gate Charge	Q _{G(TH)}				2.5]	
Gate-to-Source Charge	Q _{GS}	V_{GS} = 4.5 V, V_{DS} =	15 V; I _D = 30 A		5		nC	
Gate-to-Drain Charge	Q _{GD}				2			
Gate Plateau Voltage	V _{GP}				2.5		V	
Total Gate Charge	Q _{G(TOT)}	V_{GS} = 10 V, V_{DS} = 15 V; I_D = 30 A			26		nC	
SWITCHING CHARACTERISTICS (Note 6)								
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 4.5 V, V_{DS} = 15 V, I _D = 15 A, R _G = 3.0 Ω			15			
Rise Time	t _r				7]	
Turn-Off Delay Time	t _{d(OFF)}				20		ns	
Fall Time	t _f				7		1	

5. Pulse Test: pulse width \leq 300 µs, duty cycle \leq 2%. 6. Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

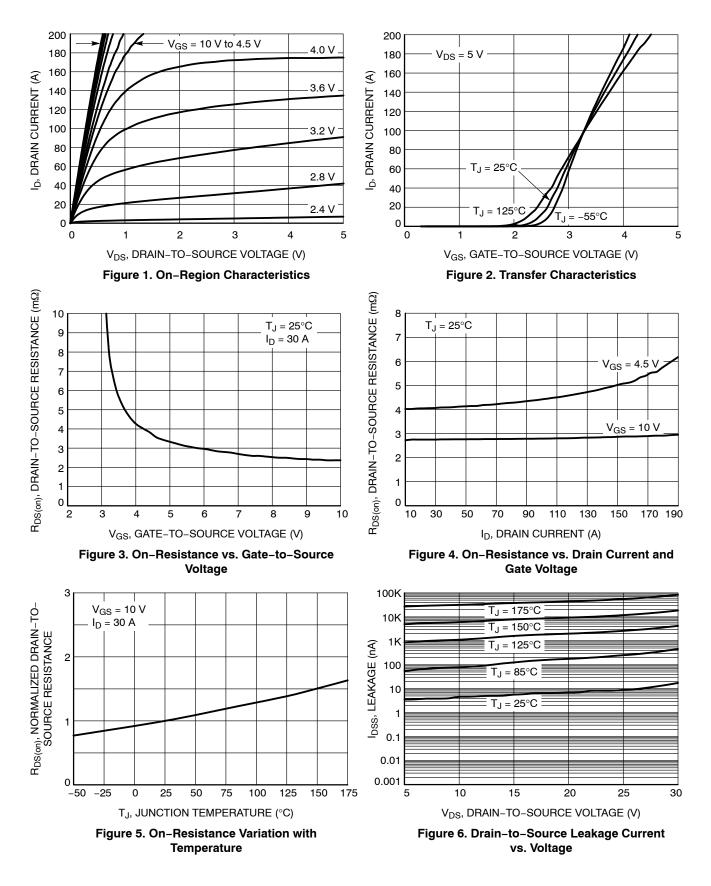
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (Note e	6)					-	
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 10 V, V_{DS} = 15 V, I _D = 15 A, R _G = 3.0 Ω			10		ns
Rise Time	t _r				3		
Turn-Off Delay Time	t _{d(OFF)}				27		
Fall Time	t _f				4		
DRAIN-SOURCE DIODE CHARACTERIS	STICS						
Forward Diode Voltage	V _{SD}	$V_{GS} = 0 V, \\ I_{S} = 30 A \\ T_{J} = 125^{\circ}C \\ T_{J} = 125^{\circ}C$			0.82	1.1	Ň
					0.69		- V
Reverse Recovery Time	t _{RR}	V _{GS} = 0 V, dIS/dt = 100 A/µs, I _S = 30 A			39		
Charge Time	t _a				16.5		ns
Discharge Time	t _b				17.6		
Reverse Recovery Charge	Q _{RR}				17		nC

5. Pulse Test: pulse width \leq 300 µs, duty cycle \leq 2%.

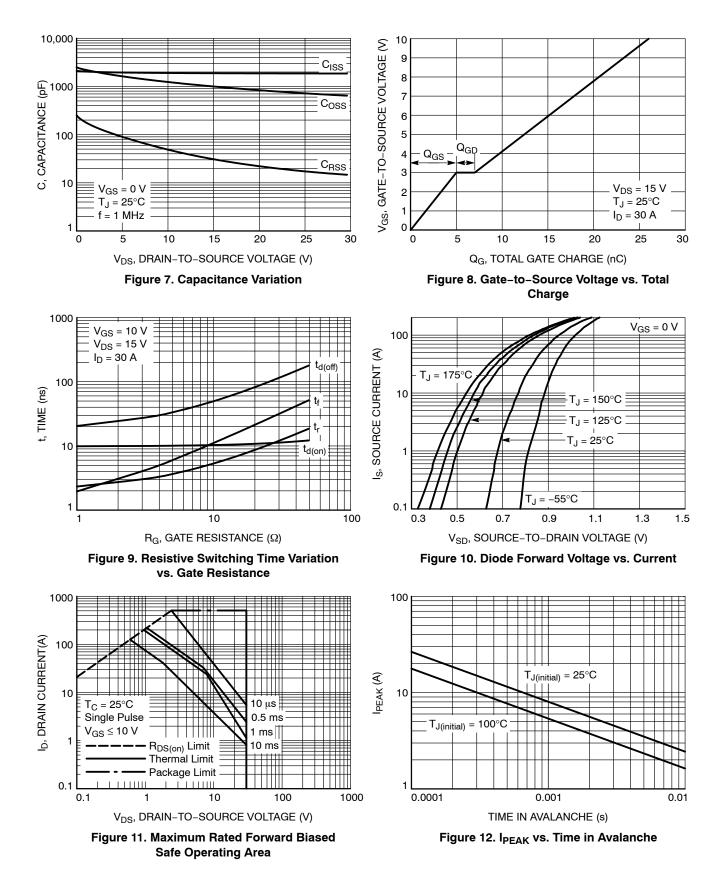
6. Switching characteristics are independent of operating junction temperatures.

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

TYPICAL CHARACTERISTICS



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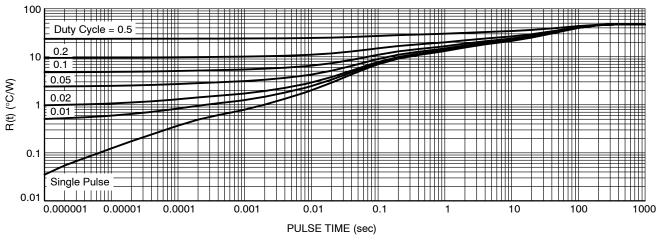
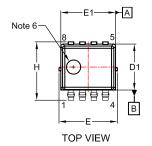
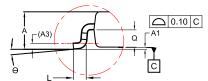


Figure 13. Thermal Characteristics

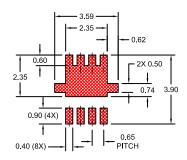
PACKAGE DIMENSIONS

LFPAK8 3.3x3.3, 0.65P CASE 760AD ISSUE E



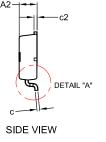


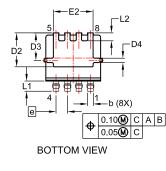
DETAIL 'A' SCALE: 2:1



LAND PATTERN RECOMMENDATION

*FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.





NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS OR BURRS SHALL NOT EXCEED 0.150mm PER SIDE.
- DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 5. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.
- 6. OPTIONAL MOLD FEATURE.

DIM	MILLIMETERS				
DIM	MIN.	NOM.	MAX.		
А	0.95	1.05	1.15		
A1	0.00	0.05	0.10		
A2	0.95	1.00	1.05		
A3		0.15 RE	F		
b	0.27	0.32	0.37		
С	0.12	0.17	0.22		
c2	0.12	0.17	0.22		
D1	2.50	2.60	2.70		
D2	1.82	1.92	2.02		
D3	1.46	1.56	1.66		
D4	0.20	0.25	0.30		
E	3.20	3.30	3.40		
E1	3.00	3.10	3.20		
E2	2.15	2.25	2.35		
е	(0.65 BSC	;		
Н	3.20	3.30	3.40		
L	0.25	0.37	0.50		
L1	0.48	0.58	0.68		
L2	0.35	0.45	0.55		
Q	0.45	0.50	0.55		
θ	0°	4°	8°		

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